Se	arch	Note	S
EMB (BIII			IBIE



Application/Control No.	Applicant(s)/Patent under Reexamination	
09/666,087	UKIGAWA ET AL.	
Examiner	Art Unit	
Hussein A. El chanti	2157	

	SEARCHED		
Class	Subclass	Date	Examiner
709	203 206-207 223-224 246	3/28/2005	HE

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
709	246 207	4/12/2005	HE
709	203	4/12/2005	HE

SEARCH NOT)
	DATE	EXMR
East search (see attached serarch report)	3/28/2005	HE
NPL search (google search, IEEE search)	3/28/2005	HE
Consulted with primary examiner Mustafa Meky A.U. 2157 (performed WEST search)	3/28/2005	HE